

# Magneto- Optics Properties of Graphite

Wala Dizayee<sup>1,2</sup>, Yalei Wang<sup>3</sup>, A. Mark Fox<sup>1</sup> and Gillian A. Gehring<sup>1</sup>

<sup>1</sup> Department of Physics and Astronomy, University of Sheffield, Sheffield S3 7RH, UK

<sup>2</sup>Department of Science, Salahaddin University, Erbil, Iraq

<sup>3</sup> Key Laboratory of Magnetic Molecules and Magnetic Information Materials of Ministry of Education and School of Chemistry and Materials Science, Shanxi Normal University, Linfen 041004, P. R. China

[w.dizayee@sheffield.ac.uk](mailto:w.dizayee@sheffield.ac.uk)

## Abstract:

Faraday rotation is one of the most important magneto-optical phenomena and is used in spintronics research where is used to study the polarization of electron spins [1]. In this work we prepare thin graphite films in order to measure the Faraday rotation for graphite in the visible region of the spectrum order to compare it with theory [2].

We used two techniques to produce thin films. Pulsed laser deposition using an excimer XeCl laser with an operating wavelength of 308 nm produced the best films. Films were also grown using spin coating, but this produced poor quality films that appeared dark.

The magneto-optic spectrum is measured using the method of Sato [3] during which the magnetic circular dichroism MCD is measured simultaneously with the Faraday rotation. There are no available calculations of the MCD for graphite. A xenon lamp (150W), with an energy range of (1.5-4.5 eV) been used for our measurements and an electromagnet with an attainable maximum field of 1.8T. The magnetic field is perpendicular to the plane of the sample and parallel to the direction of incidence.

A Dektak surface profiler is employed in order to measure the samples thickness. In addition, the thicknesses of the films have been estimated from the optical absorption using parameters taken from the bulk, by taking account of the reflections from the front and back sides of the film [4] as shown in Figure1.

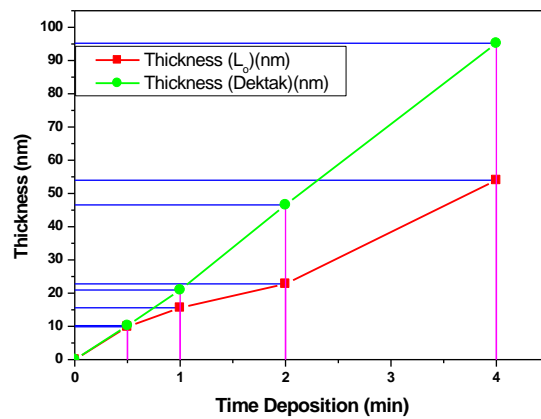
Both measurements showed that the thickness is dependent on the deposition time. The surface topography and the structural changes of the films were characterized by scanning electron microscopy (SEM), and AFM scanning probe microscopy shown in Figure2. The SEM measurements show a flat surface topography, however a height variation of ( $\pm 5$ nm) was detected by AFM for a film of thickness approximately (20nm). The XRD shows two peaks, one for small crystallites of graphite (002) and the second for the sapphire substrate (Figure3) [5].

Results for the Faraday rotation and MCD in the range 1.5eV to 4.5eV will be presented and compared with the theory.

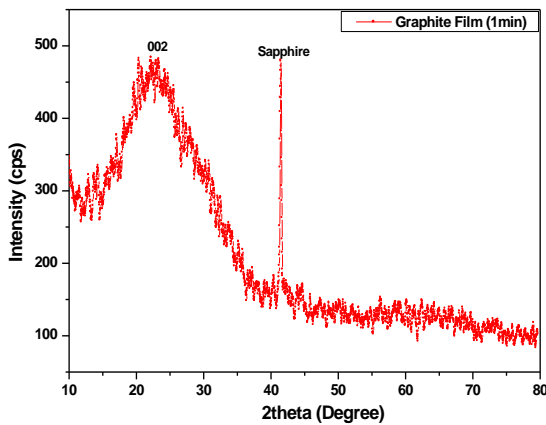
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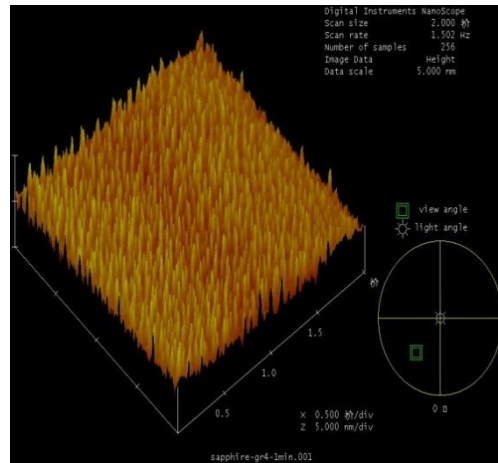
**Figures:**



**Figure1: Graphite film Thickness by Dektak (Green) and optical density (Red).**



**Figure3: XRD spectrum of synthesized Graphite thin films.**



**Figure2: AFM for Graphite (1min)**